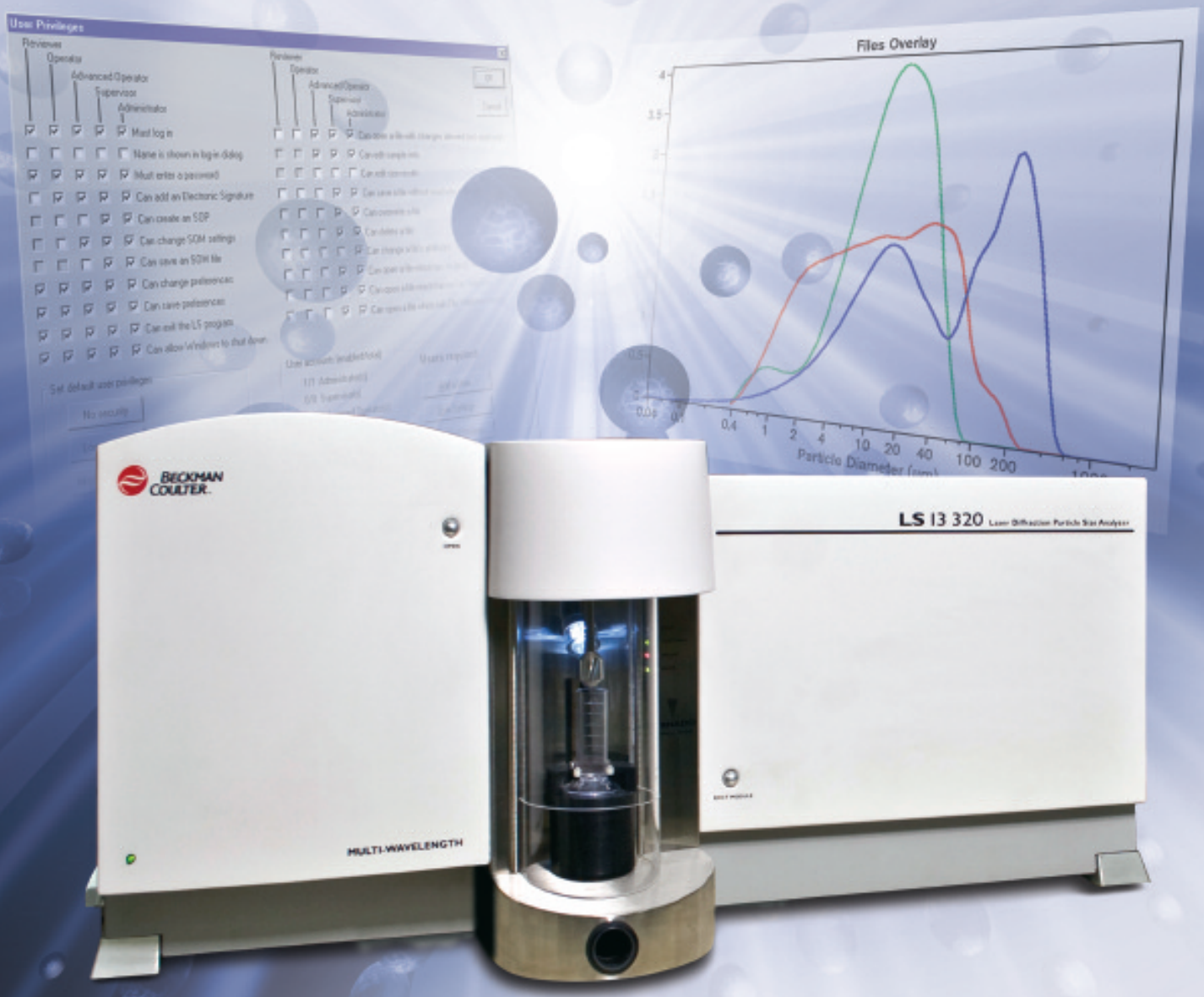
Meeting and exceeding the standard for laser diffraction particle size analysis.

LS 13 320 Particle Size Analyzer

Blood Banking
Capillary Electrophoresis
Cell Analysis
Centrifugation
Genomics
Lab Automation
Lab Tools
Particle Characterization



BR-9809B

LS 13 320

Integrated smart solutions for laser diffraction particle size analysis

The LS 13 320 Series is the most versatile and sophisticated laser diffraction particle size analyzer available today. Using the Fraunhofer and Mie theories of light scattering, the LS 13 320 Series offers the highest resolution, reproducibility and unsurpassed accuracy. All this, so you can count on the results generated by the LS 13 320 Series. In fact, the LS 13 320 can measure unknown sample distributions without having the analyst guess the type of distribution mode to preprogram the instrument.

Depending on your applications and requirements, two options of optical benches are available: the single-wavelength system covering a size range from 0.4 µm to 2,000 µm and the flagship multi-wavelength system incorporating Beckman Coulter's Polarization Intensity Differential Scattering (PIDS) technology covering a size range from 0.017 µm to 2,000 µm.

Our latest generation of sample-handling modules has been designed for flexibility and convenience, offering varying degrees of automation. To save operators valuable time, all modules "auto-dock" in seconds and are automatically configured and recognized by the optical bench due to their "plug-and-play" capabilities. To facilitate meeting compliance requirements, all the module functions are fully controlled via Standard Operating Methods (SOM's) and Standard Operating Procedures (SOP's), making their operation simple and ensuring that all instrument conditions and settings remain constant for any given sample. If full automation is required, the Auto Prep Station is available with up to 30 samples for walk-away routines.

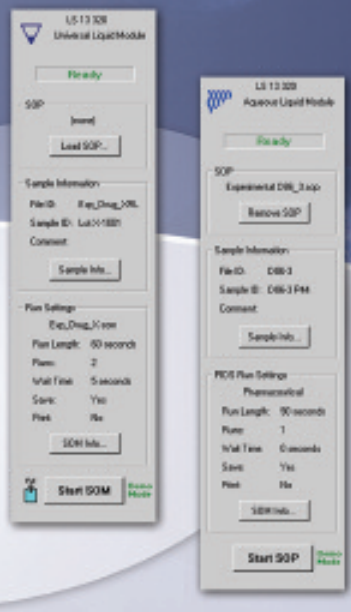
Equally at home in research and development, quality control and manufacturing, the LS 13 320 particle size analyzer provides the analyst with a system that is easy to use, producing fast and reliable results, yet technically advanced for dry, aqueous and non-aqueous samples to satisfy all your particle sizing needs.

Step 1

Load your SOM or SOP

Step 2

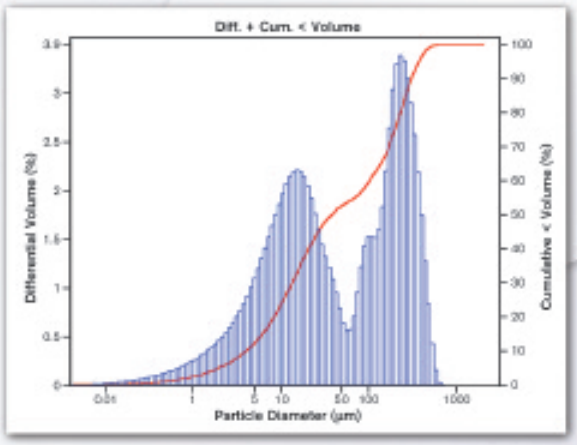
Click Start SOM or SOP

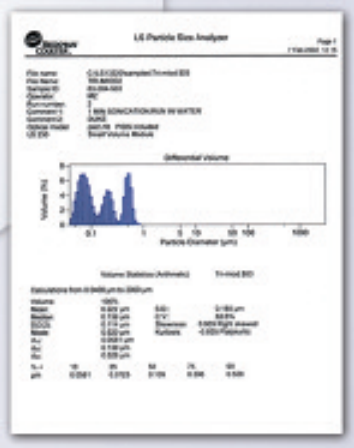


Power, flexibility and simplictiy are the driving force behind the LS 13 320 software.

Step 3

Get results





Presenting your results in a flexible way

The LS 13 320 software offers great flexibility when presenting your results. Whether for pharmaceutical, industrial, quality control, or research applications, the software will satisfy any requirements for data presentation.

Efficient data management

The LS 13 320 software allows the customization of data output and printed reports. Through the use of SOP's or preference files, design the report that best fits your needs.

SOM & SOP

Standardize your process with Standard Operating Procedures and Methods

Establishing the SOM is quick, simple and foolproof

With Standard Operating Methods and Procedures, you can ensure your analyses are the same run after run.

The use of SOM's and SOP's guarantee consistency and uniformity of your results, regardless of the instrument settings, operators and locations.

Step 1

Set up your SOM and sample description

Step 2

Identify your sample

Step 3

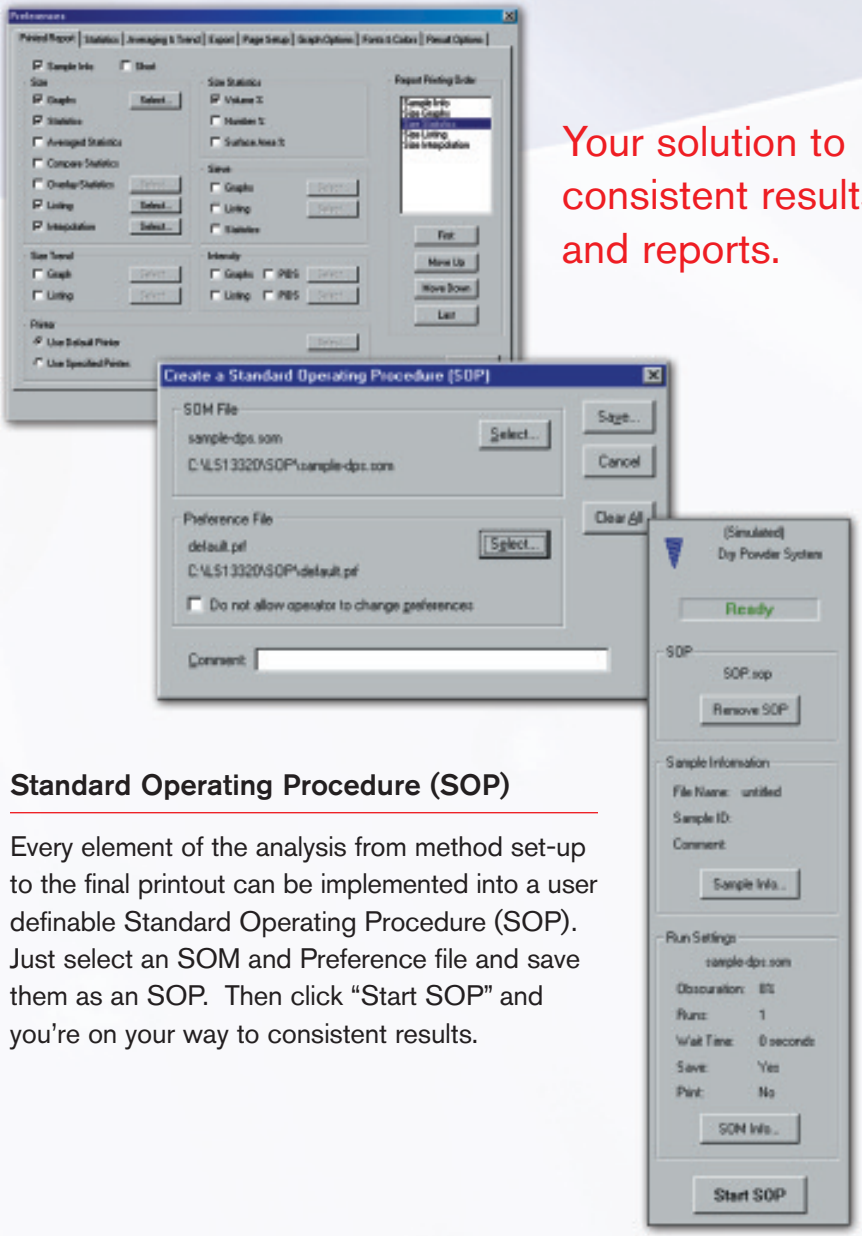
Set up your anlaysis parameters

Step 4

Choose your optical model

Step 5

Save your SOM



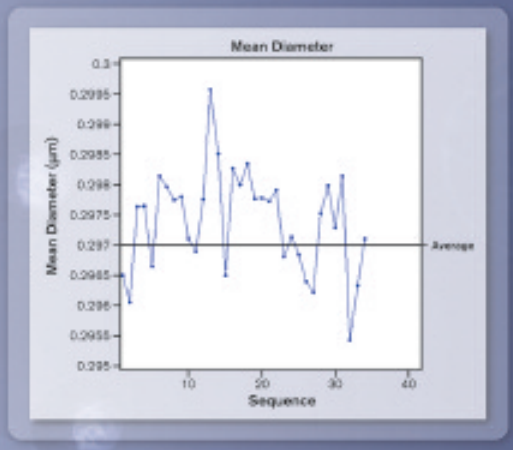
Your solution to consistent results and reports.

Standard Operating Procedure (SOP)

Every element of the analysis from method set-up to the final printout can be implemented into a user definable Standard Operating Procedure (SOP). Just select an SOM and Preference file and save them as an SOP. Then click "Start SOP" and you're on your way to consistent results.

Size Trend

The Size Trend function is used to plot the statistics of several sample runs on one graph or report. This can help you keep track of your specific process since the files can be updated as often as necessary.

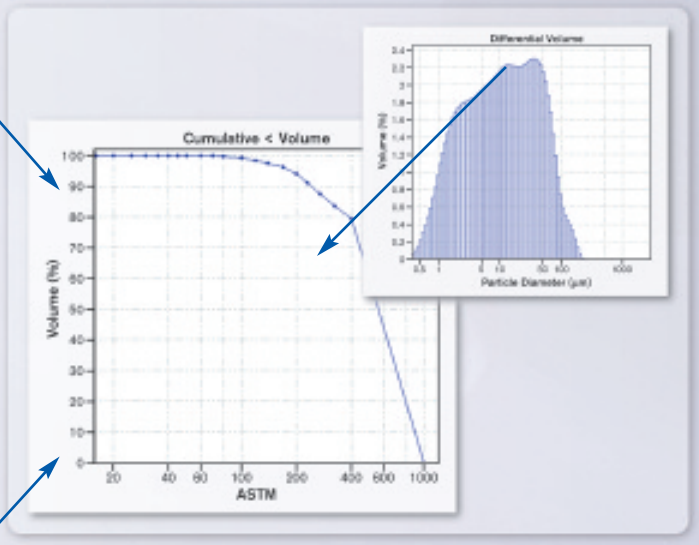


Software designed with the user in mind.

Sieve Analysis

The Sieve Analysis function allows you to view the data obtained from your LS 13 320 in a sieve format if you need to compare old sieve data.

ASTM	Cum. < Volume %
999	0
400	79.5164
325	83.6407
270	87.4781
230	91.1161
200	94.0814
170	96.2735
140	97.5502
120	98.4782
100	99.2856
80	99.8087
70	99.9786
60	99.9993
50	100
45	100
40	100
35	100
30	100
25	100
20	100

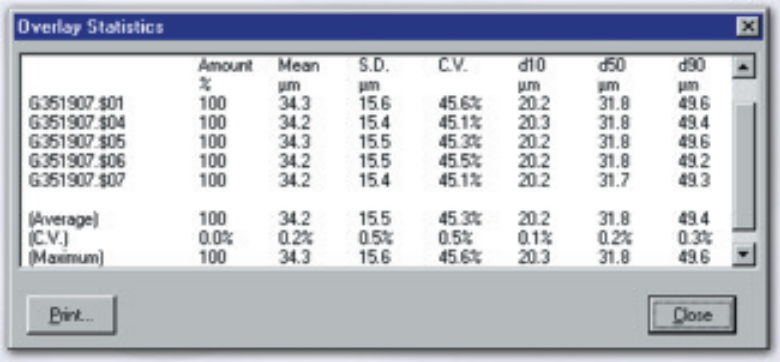


Interpolation

The LS 13 320 software can be used to create sample reports that will arrange the data to conform to a set of user defined “size classes” through the Size Interpolation function.

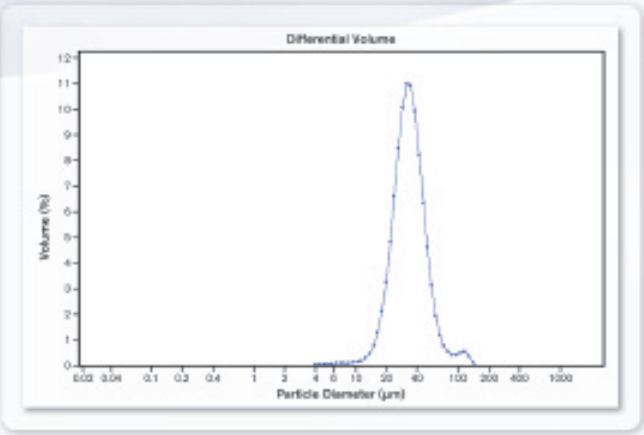
ISO 13 320 *Meeting and exceeding the standard*

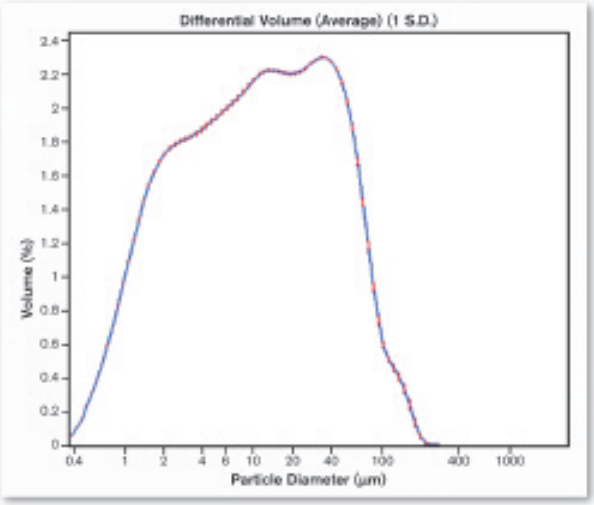
With the publication of the International Standard ISO 13320, Particle size analysis — Laser diffraction methods, it becomes possible for users to evaluate statistics within a scientific frame of reference.



Accuracy

The response of the laser diffraction instrument is considered to meet this standard if the mean value of the X_{50} coming from at least three independent measurements deviates less than 3% from the certified range of values specified for the material, i.e. the mean value together with its standard deviation; the mean values for the X_{10} and X_{90} should deviate less than 5% from the certified range of values.





An average of 10 separate runs showing the spread of results with error bars of one standard deviation.

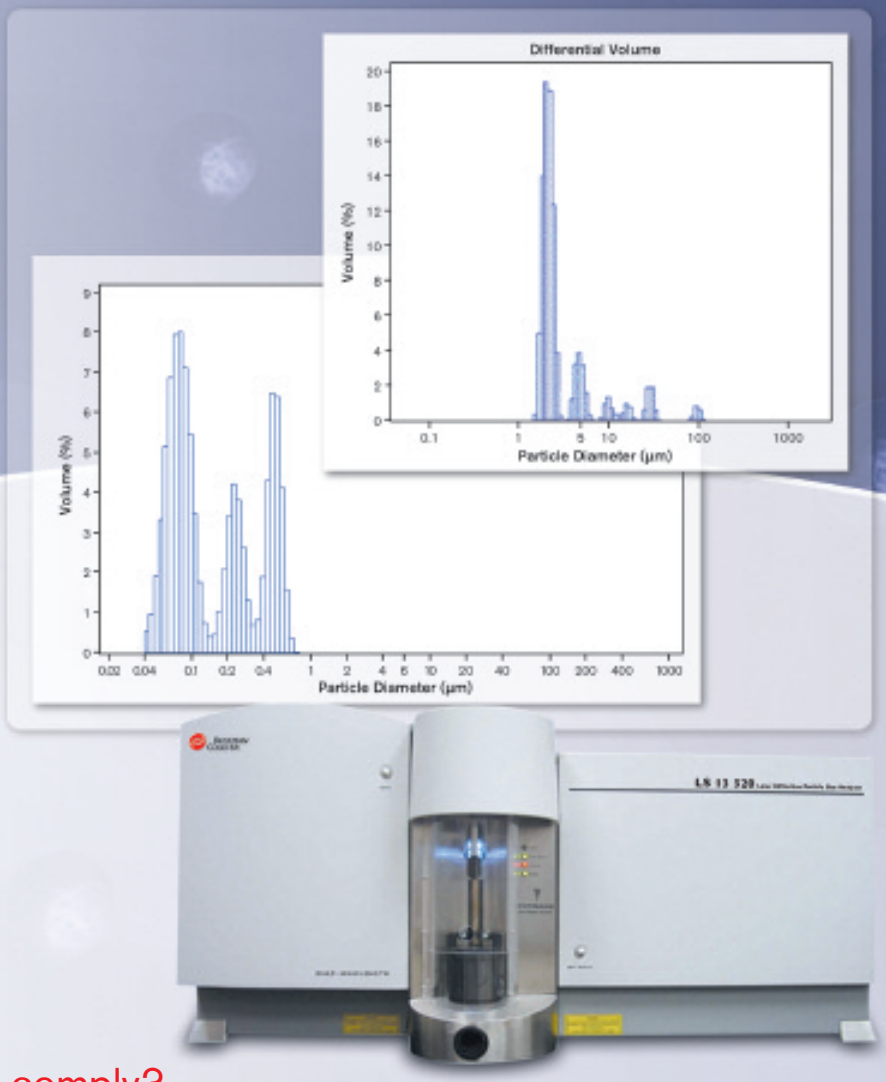
Repeatability

The repeatability of characteristic particle sizes in size distributions should be as follows: for any chosen central value of the distribution, e.g. the median size (X_{50}), the coefficient of variation should be smaller than 3%. Values at the sides of the distribution, e.g. X_{10} and X_{90}, should have a coefficient of variation not exceeding 5%.

Resolution & Sensitivity

The resolution of the particle size distribution, i.e. capability to differentiate between different particle sizes, and the sensitivity for small (extra) amounts of particles of certain size are restricted by the following factors:

- Number, position and geometry of the detector elements
- Signal to noise ratio
- Fine structure in the measured scattering pattern
- Difference in scattering pattern between size classes
- Actual size range of the particulate material
- Adequacy of the optical model
- Smoothing applied in the deconvolution procedure



How does the LS 13 320 comply?

Accuracy

- Custom designed X-shaped detector array allows the most accurate measurement to be obtained for the characterization of the scattering pattern, which ultimately leads to the most accurate results possible
- The PIDS system delivers unrivaled accuracy in the submicron region by taking 36 detection measurements for this region alone. No other comparable system offers this degree of capability in the submicron region

Resolution & Sensitivity

- High number of log-spaced detectors provide a clear difference in scattering pattern between size classes
- Continuous averaging amplification circuitry to increase signal-to-noise ratio
- No requirement to pre-select curve fitting routines as with other manufacturers, meaning the user has no need to have an understanding of the nature of the distribution prior to the analysis
- Full and complete invocation of both Fraunhofer and Mie theories, including the use of multi-wavelength modeling, ensures the user can make most benefit of the available raw data

Repeatability

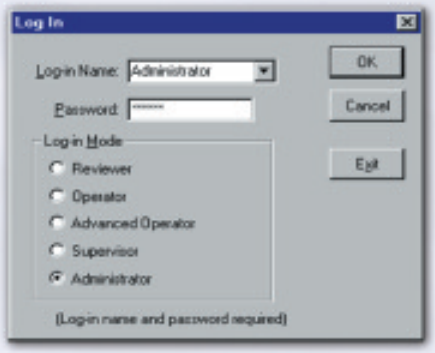
- The automatic alignment system ensures accurate angular calibration of the laser with respect to the optical path. The benefit of this is that the scattered light from any particulates in the sample cell will fall on the correct detectors from an angular perspective, offering reproducible results time after time
- High quality components throughout the LS 13 320 design

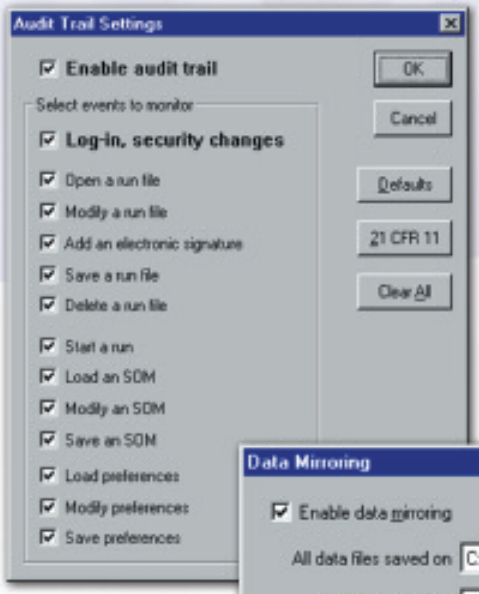
Security *21 CFR Part 11 and instrument qualification process*

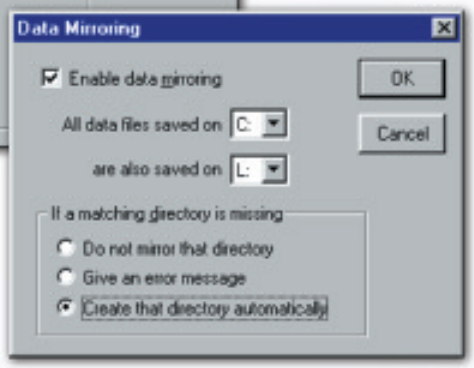
Security

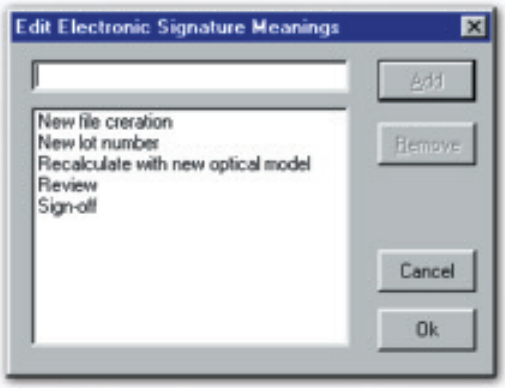
The LS 13 320 software comes with a configurable security system. The user can choose between 5 levels of security, from No security to 21 CFR Part 11, the choice is yours. Choosing 21 CFR Part 11 configures the software to be compliant to 21 CFR Part 11, the FDA regulation covering electronic signatures and records.

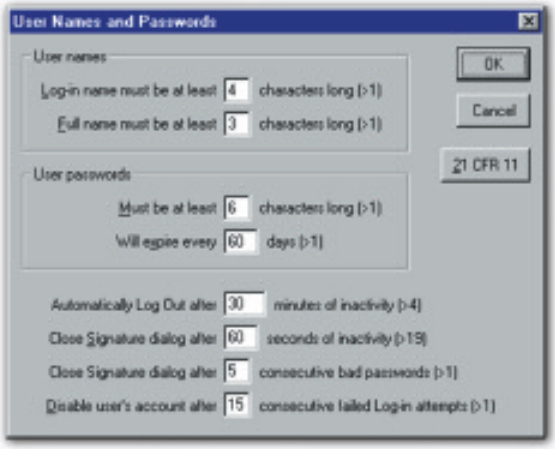
One click away from compliance.



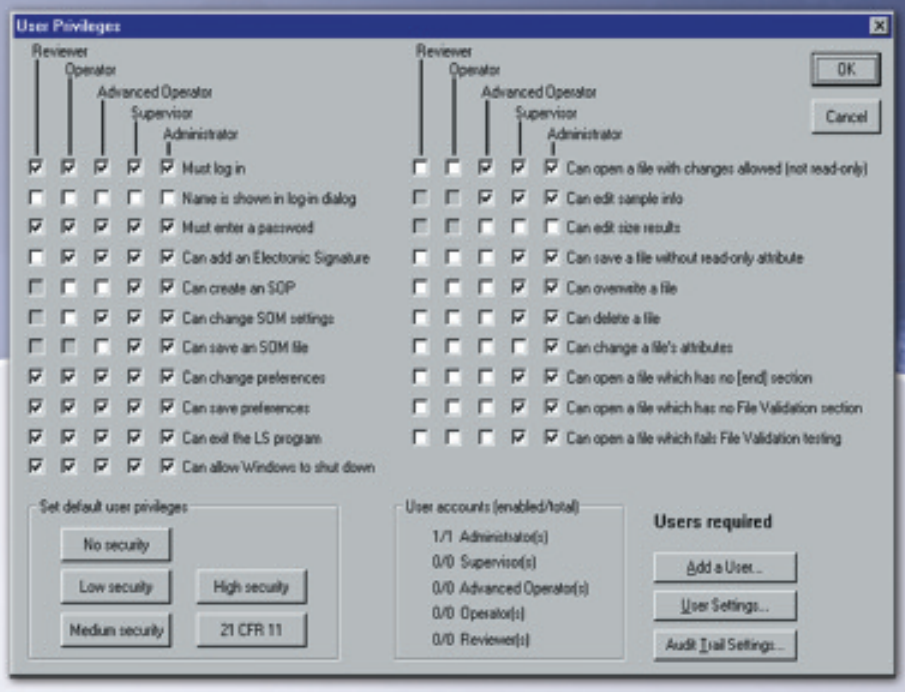








Regulatory Compliance



The Electronic Records and Electronic Signatures Rule (21 CFR Part 11) was established by the FDA to define the requirements for submitting documentation in electronic form and the criteria for approved electronic signatures. This rule, which has been in effect since August 20, 1997, does not stand in isolation; it defines the standards by which an organization can use electronic records to meet its record-keeping requirements. Organizations that choose to use electronic records must comply with 21 CFR Part 11. It is intended to improve an organization's quality control while preserving the FDA's charter to protect the public. Since analytical instrument systems such as the LS 13 320 generate electronic records, these systems must comply with the Electronic Records Rule. By selecting the 21 CFR Part 11 option in the software, the system automatically reconfigures to comply with these regulations. In addition to the 21 CFR Part 11, the software offers other security levels that may be customized by the user.

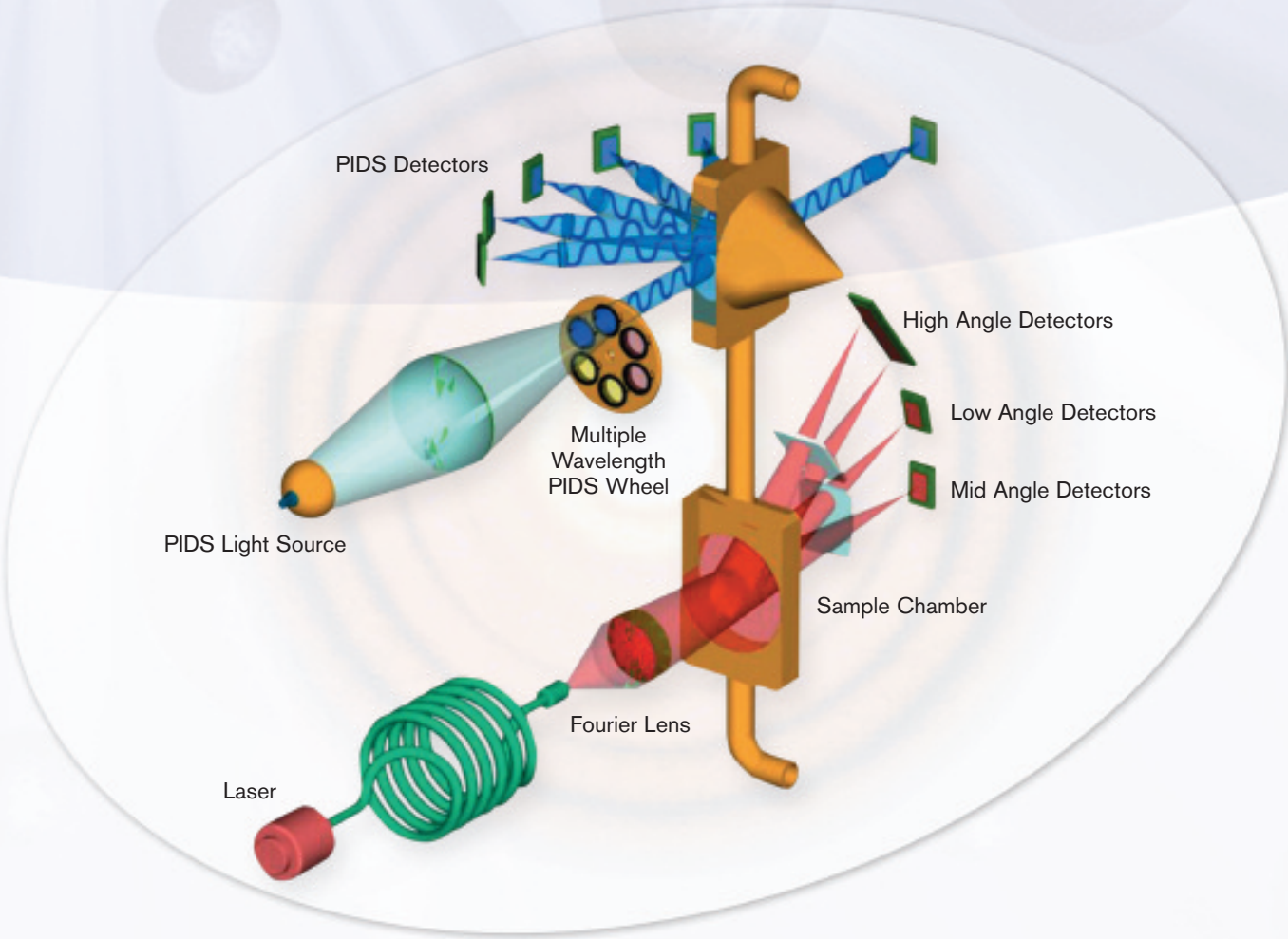
V-Check Program

The V-Check Program is a comprehensive package that covers appropriate aspects of a product's life cycle, from instrument development to verification (e.g. SQ, DQ, IQ, OQ). The V-Check Program contains the necessary documentation for instrument validation. It consists of a number of functional inter-linked components, which have been designed to give you assurance that the product is fit for its designed purpose and will deliver consistent performance. Where other instrument manufacturers leave off, Beckman Coulter and its V-Check Program assist with ongoing quality checks of the instrument – demonstrating the value of a manufacturer who not only understands your needs, but is also willing to develop a partnership for the future.

Operating Principles

Beckman Coulter Firsts:

- ***First company offering wide dynamic range without changing lenses***
- ***First company with auto-alignment***
- ***First company to utilize four wavelengths***
- ***First and only company to incorporate scattering technology – PIDS***



The scattering of light is one of the most widely used techniques for measuring the size distribution of particles.

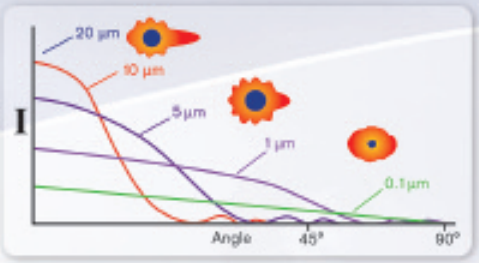
It is a fast and flexible technique that offers even the novice user the chance to obtain high quality data.

The basis of the method is simple: a laser light source is used to illuminate particulates, usually contained within a suitable sample cell. The light scattered by the particles is then detected by silicon photo-detectors.

The intensity of light on each detector measured as a function of angle, is then subjected to mathematical analysis using a complex inversion matrix algorithm. The result is a particle size distribution displayed as volume % in discrete size classes.

PIDS
Polarization Intensity Differential Scattering

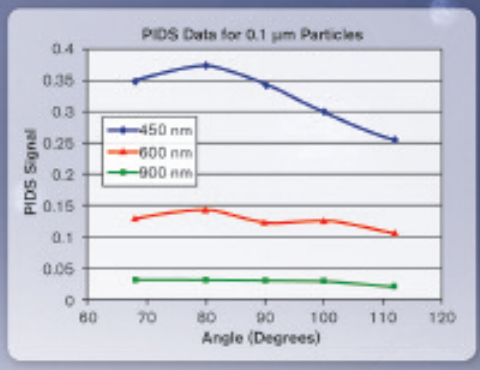
Why use PIDS for sizing sub-micron particles rather than the standard forward low-angle scattering technologies employed by other instrument manufacturers? Particles below a few microns in diameter have very similar light scattering patterns that are alike in both shape and intensity. These physical properties make it difficult to distinguish the differences between such patterns, which means inaccurate sizing with low resolution, resulting in a high degree of uncertainty when resolving the actual particle size.



Large particles scatter light strongly at low angles and with readily detectable maxima and minima in the scattering pattern. This means that detectors placed at low angles relative to the optical path and with sufficient angular resolution can detect these maxima and minima. Conversely small particles scatter light weakly and without any discernible maxima and minima until extremely high angles of measurement are reached. This makes the detection and the resolution of the scattering pattern difficult.

Manufacturers have adopted different solutions to overcome these limitations with varying degrees of success. Most efforts have focused on the measurement of back-scattered light. While such strategies help they are not complete solutions. For this reason Beckman Coulter developed the PIDS system, allowing for the first time a complete solution to the problem of sub-micron sizing. The technology employed in PIDS is elegant yet simple and takes advantage of the Mie theory of light scattering.

PIDS relies upon the transverse nature of light i.e., that it consists of a magnetic vector and an electric vector at ninety degrees to it. If for example the electric vector is 'up and down' the light is said to be vertically polarized.



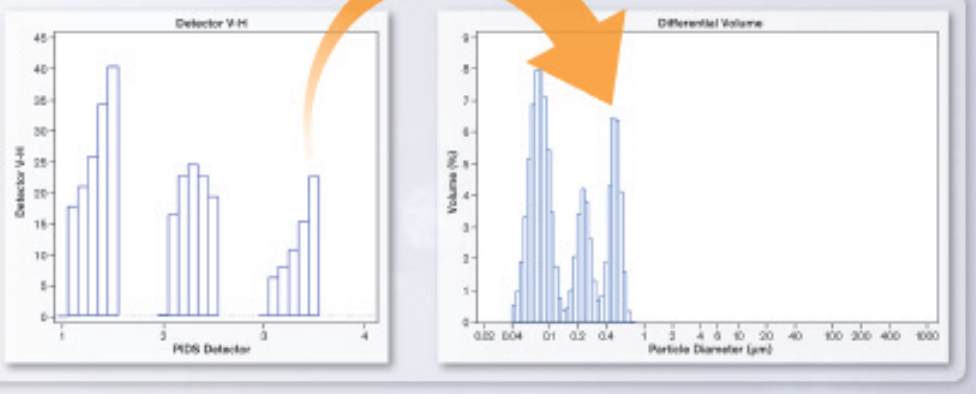
When a sample is illuminated with a light of a given polarized wavelength, the oscillating electric field establishes a dipole, or oscillation, of the electrons in the sample. These oscillations will be in the same plane of polarization as the propagated light source. The oscillating dipoles in the particles radiate light in all directions except that of the irradiating light source.

PIDS takes advantage of this phenomenon. Light at three wavelengths (450 nm, 600 nm, and 900 nm) sequentially irradiates the sample, with first vertical and then horizontal polarized light. The LS 13 320 measures the scattered light from the samples over a range of angles. By analyzing the differences between the horizontally and the vertically radiated light for each wavelength, we gain information about the particle size distribution of the sample. It is important to remember that we are measuring the differences between the vertically and the horizontally polarized signals, and not simply the values of a given polarization.

The intensity vs. scattering angle information from the PIDS signals is then incorporated into the standard algorithm from the intensity vs. scattering angle data from the laser light scattering to give a continuous size distribution.

Another major benefit of acquiring PIDS data is that by simple interpretation of the raw data we can quickly confirm whether small particles are genuinely present or not, as large particles do not exhibit the differential signal shown by small particles.

Benefit from the increased sensitivity and performance – real data means real results.



Sample Modules

Aqueous Liquid Module (ALM)

- For samples requiring suspension in aqueous systems
- Auto rinsing, auto filling and auto dilution for maximum speed and throughput
- Sample sonication for the ultimate dispersion control
- When coupled to the Auto Prep Station offers full automation

Micro Liquid Module (MLM)

- Use when only small quantities of sample are available
- Small amounts (12 mL) of volume required, particularly useful for hazardous dispersants as waste is minimized
- For use with both organic solvents and aqueous systems, giving the user maximum flexibility

Tornado Dry Powder System (DPS)

- Measures entire sample as required by the ISO 13 320 standard
- No sample preparation needed
- Fully automatic walk-away operation
- User-selectable vacuum pressure for maximum dispersion control

Universal Liquid Module (ULM)

- Fully automatic, with auto dilution, auto filling and auto rinsing for the ultimate ease of use
- Analyzes samples suspended in aqueous as well as non-aqueous diluents for maximum flexibility
- Hazardous waste is contained in a monitored vessel to avoid spillage and provide safe operation
- A variable speed pump allows for total dispersion control of your sample, from delicate emulsions to heavy particulates

LS 13 320 Specifications

Technology	Low angle forward light scattering with optional PIDS (Polarization Intensity Differential Scattering) technology. Full implementation of both Fraunhofer and Mie theories of light scattering
Particle Size Range	0.017 µm - 2000 µm
Power Consumption	≤ 6 amps @ 90 – 125 VAC ≤ 3 amps @ 220 – 240 VAC
Dimensions	10 in depth (25.4 cm) 39.6 in width (100.7 cm) 17 in height (44.5 cm)
Weight	71.5 lbs (32.5 kg)
Typical Analysis Time	15 - 90 sec
Illuminating Sources	Diffraction: Solid State (780 nm) PIDS: Tungsten lamp with high quality band-pass filters (450, 600 and 900 nm)
Humidity	0 - 90% without condensation
Temperature Range	10 - 40°C
Sample Modules	Micro Liquid Module (MLM) Tornado Dry Powder System (DPS) Aqueous Liquid Module (ALM) Universal Liquid Module (ULM) Auto Prep Station (APS)
Operating System	Windows 98, NT, 2000, XP, Vista

For more information on our Particle Characterization products, please visit us at www.CoulterCounter.com

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